



Interaction with CMOS and Terminal Characteristics

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Report Documentation Page

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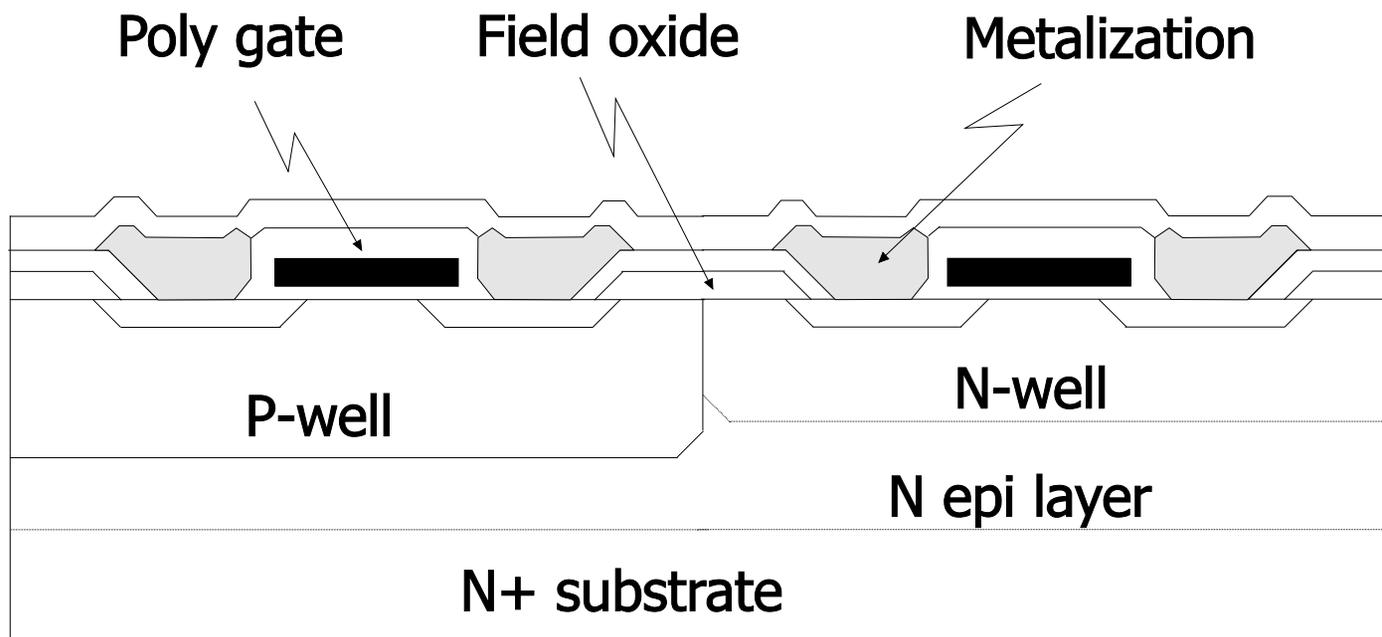
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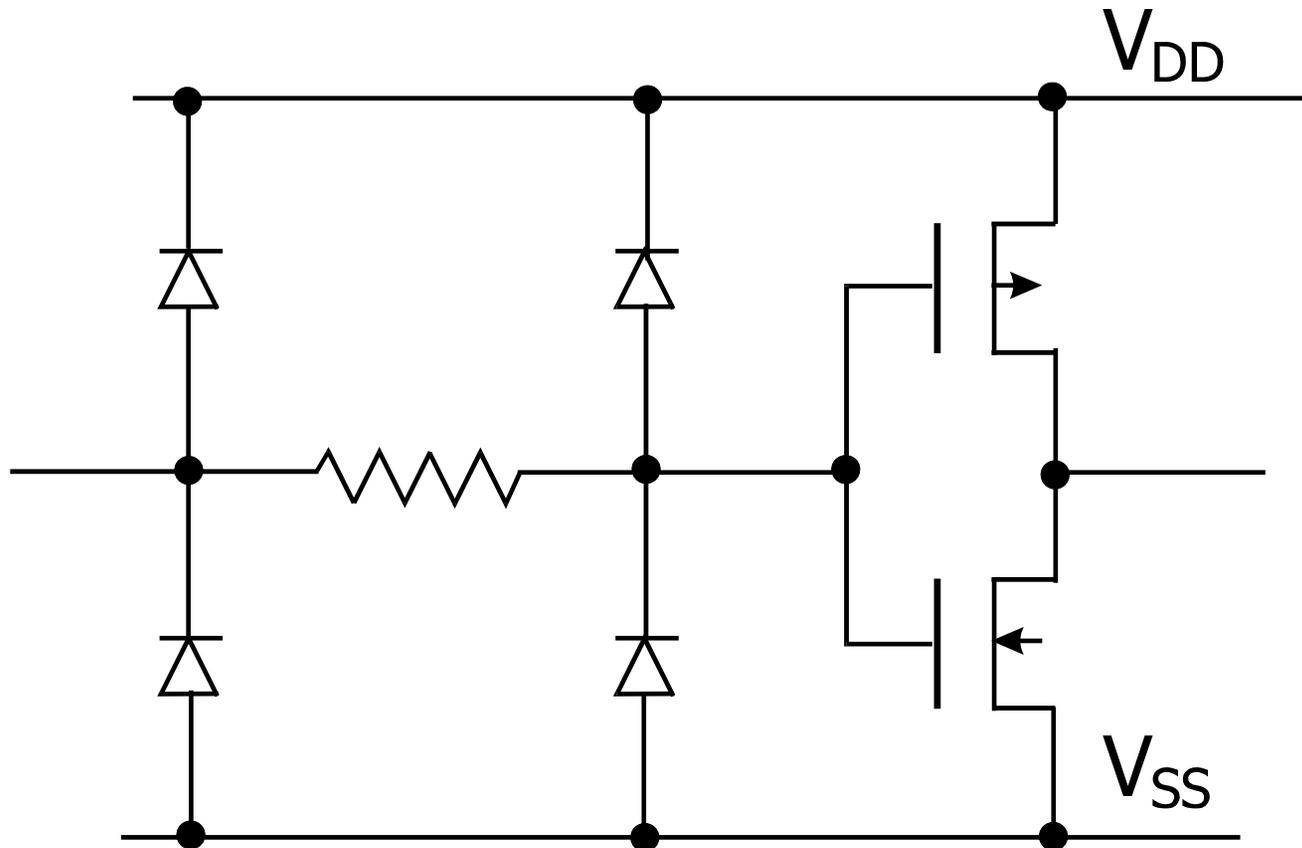
Conducted Interactions - CMOS Devices

- Mechanisms and Vulnerability Thresholds
- Impedance of Inputs through Switching
- Waveforms – Pulses and Damped Rings

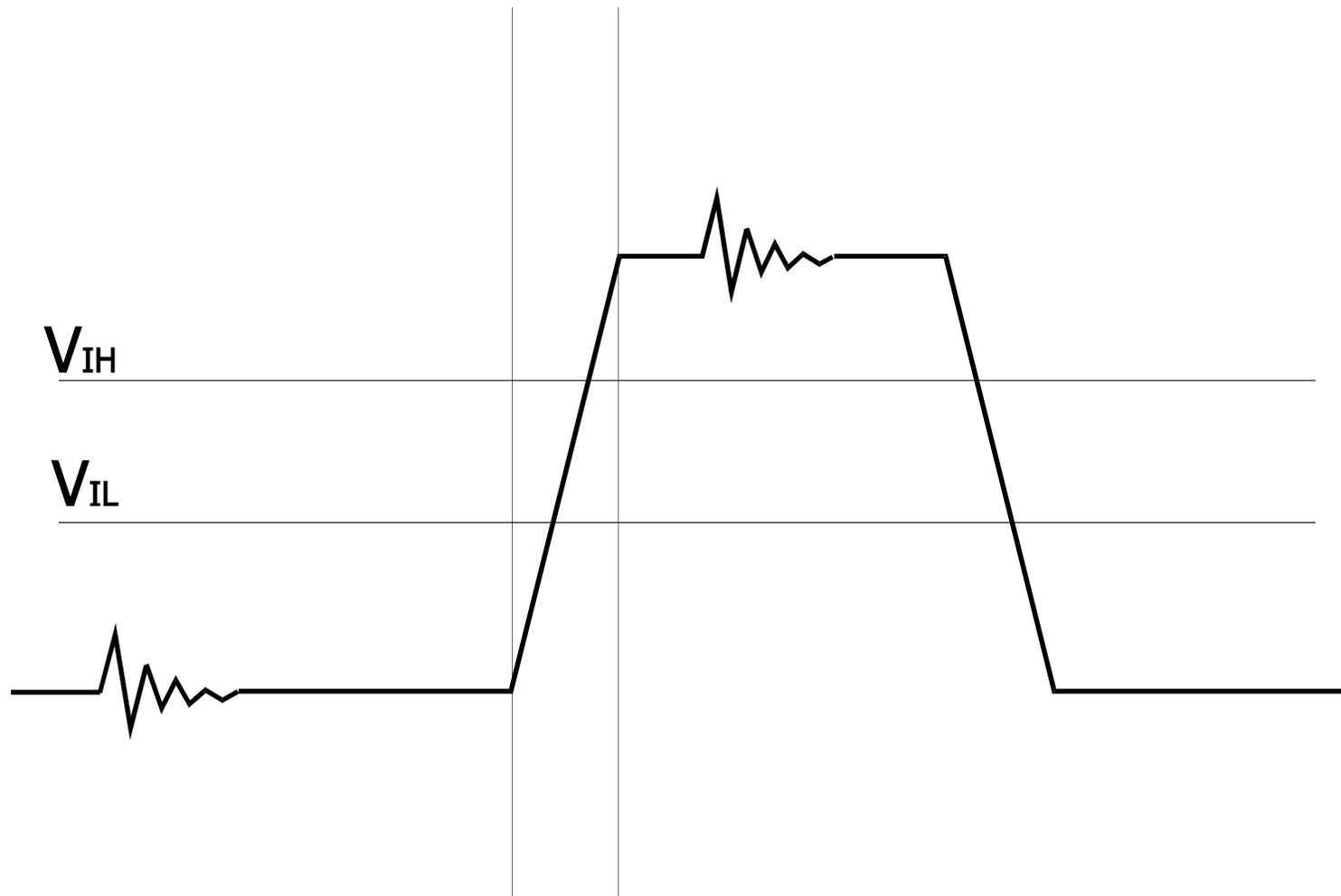
Interaction with CMOS – Mechanisms



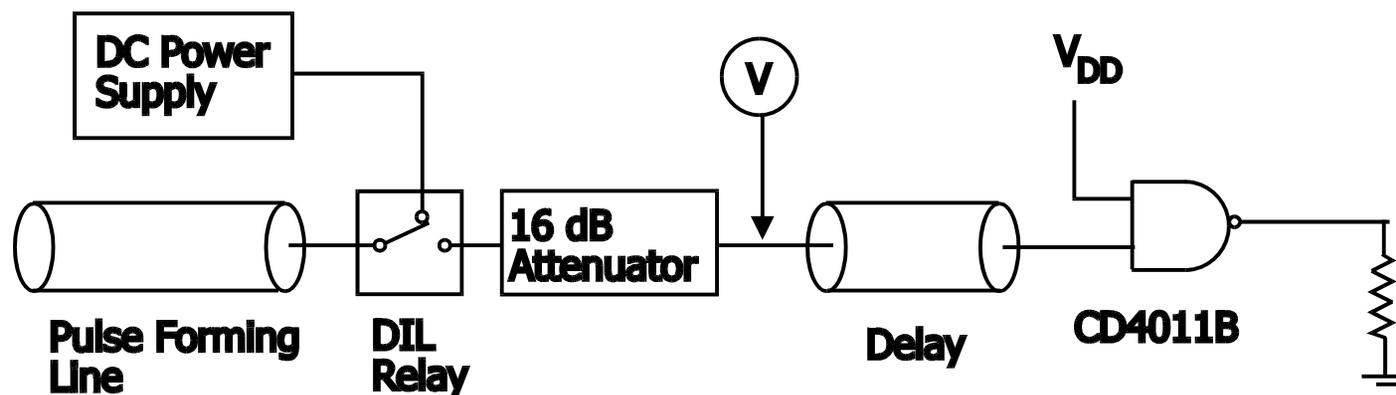
Interaction with CMOS – Input Circuit



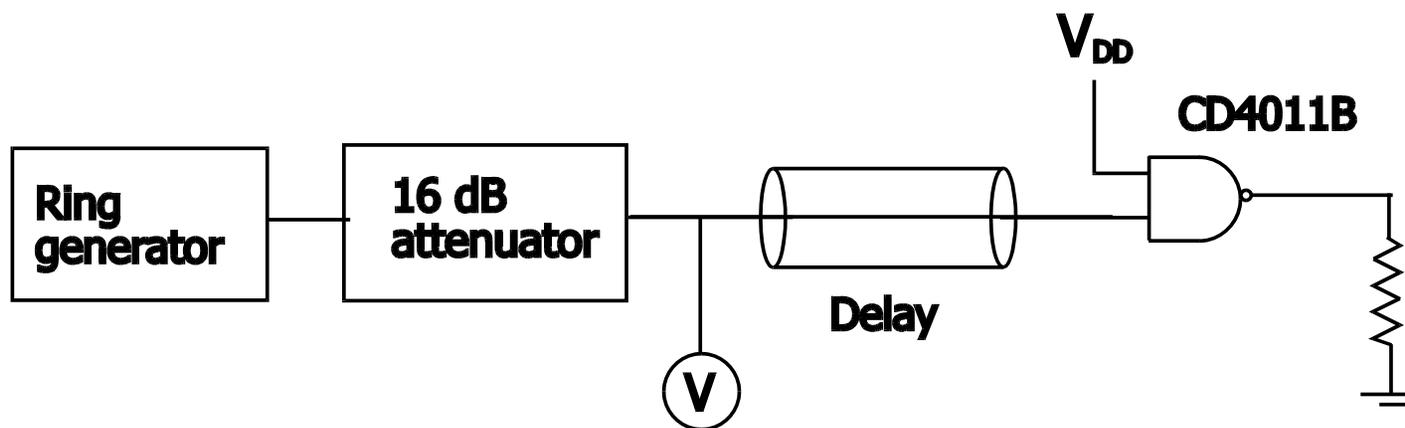
Interaction with CMOS – Ring Injection



CMOS Interactions – Injection Systems



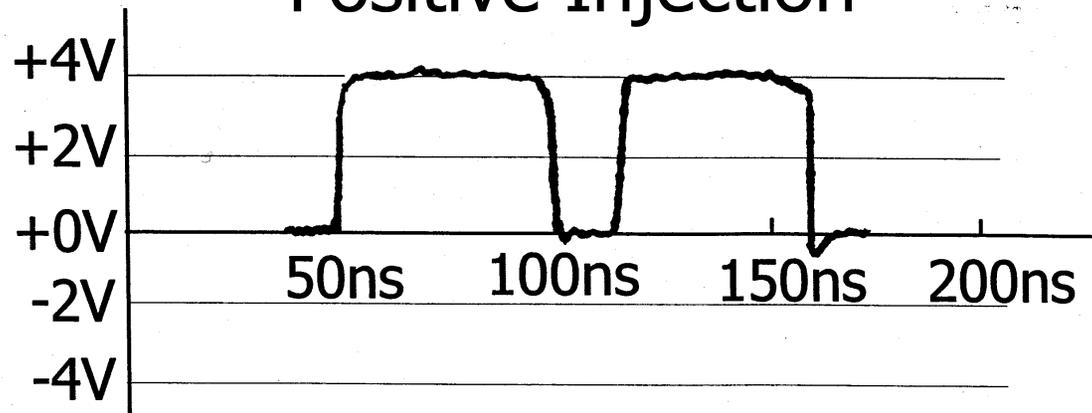
Pulse TDR System



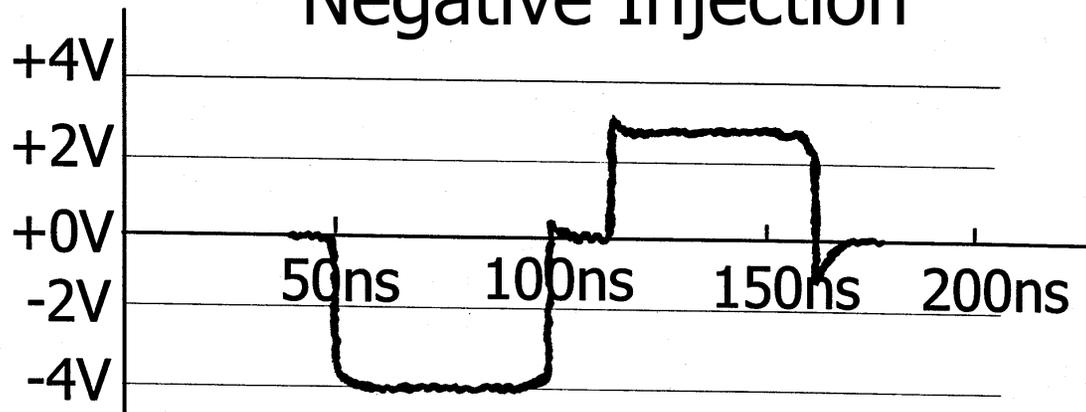
Ring TDR System

CMOS Interaction – Pulse TDR Injection

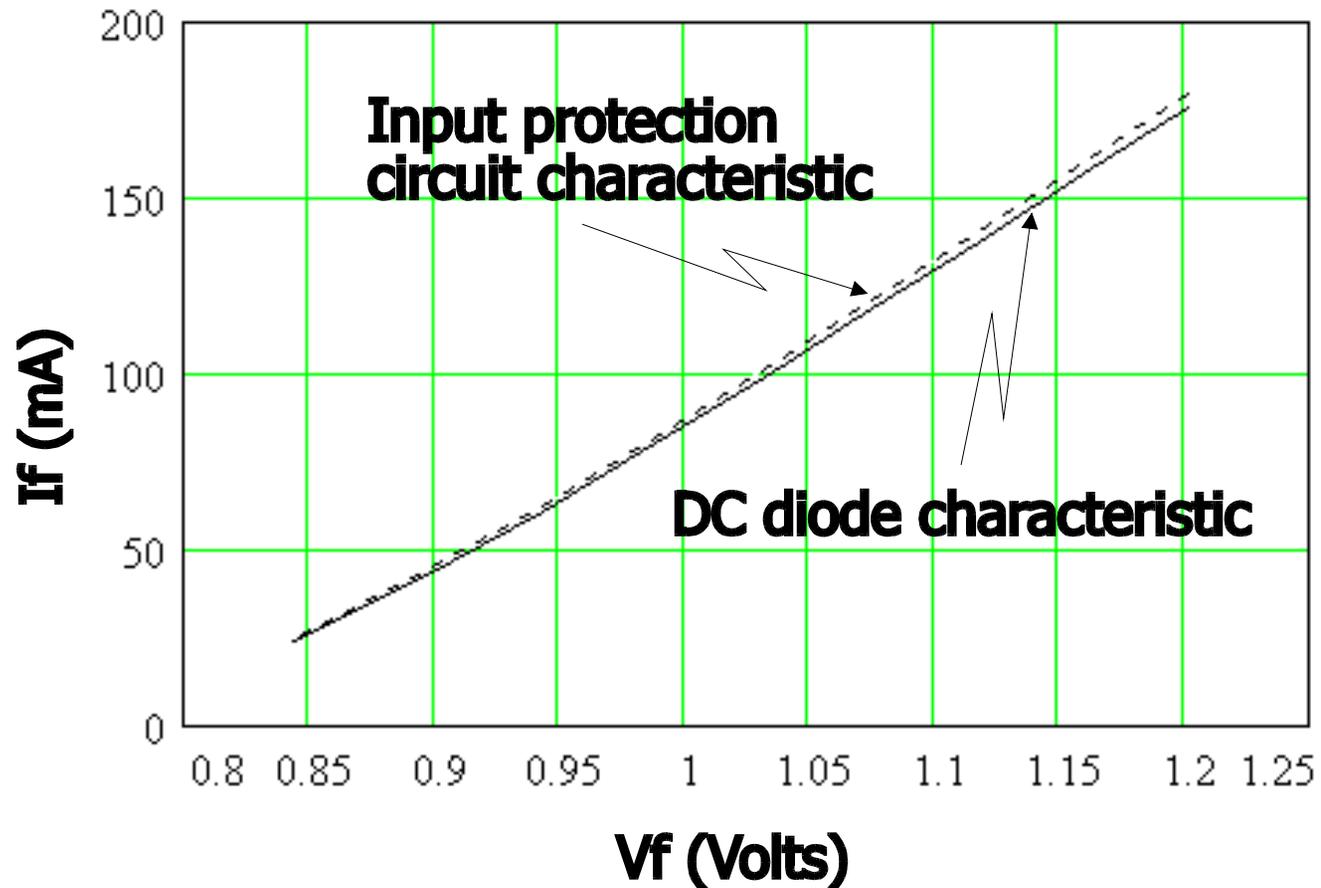
Positive Injection



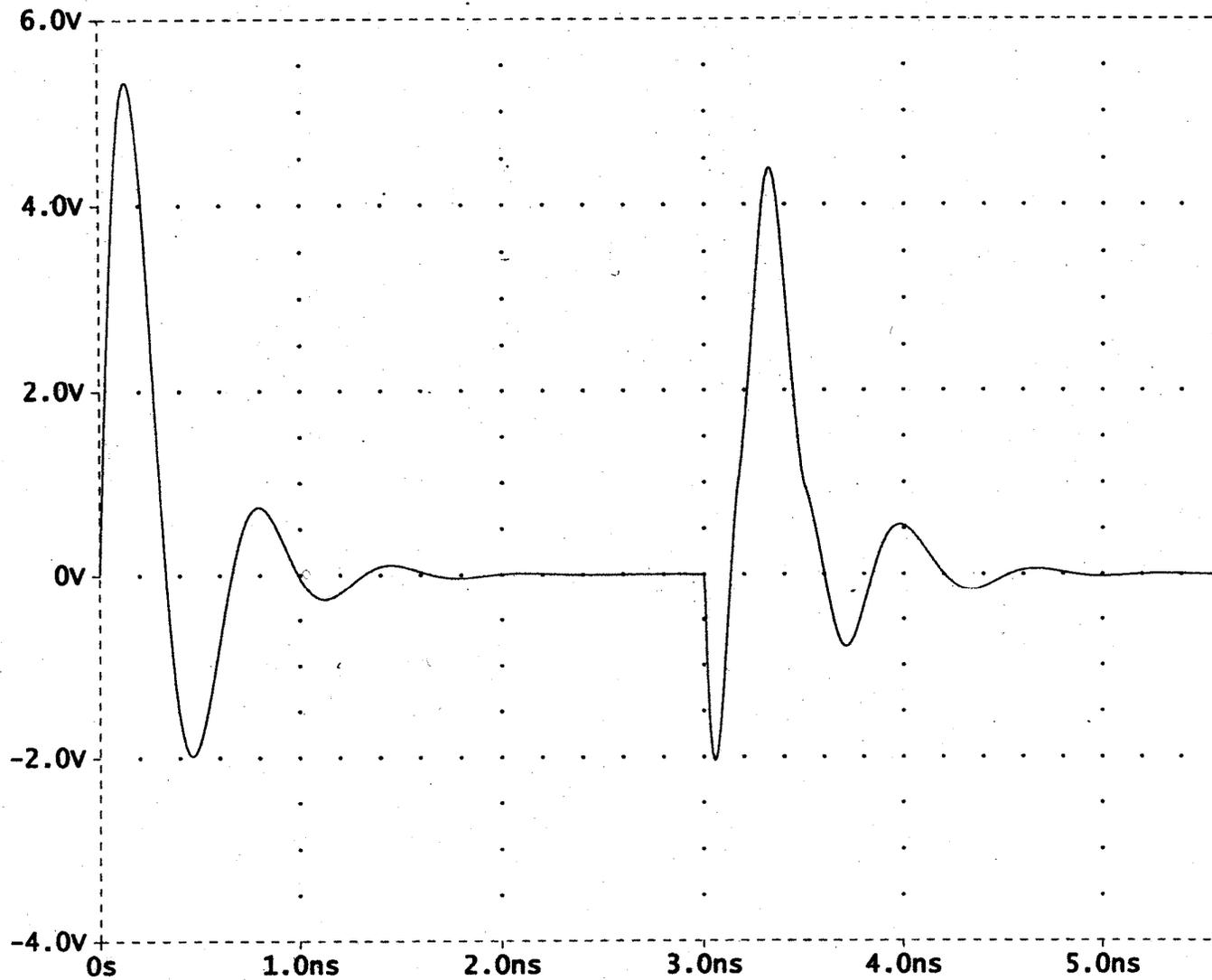
Negative Injection



CMOS Input – Pulse TDR Negative Injection



CMOS Interaction – Ringing TDR



Conducted Interactions – Future Work

- Mechanisms and Vulnerability Thresholds
- Waveforms – Pulses and Damped Rings
- Extend work to other digital devices